Issue Classification 10666316



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	Application/Control No.
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10666316 Examiner

illip H Nguyen

Applicant(s)/Patent Under Reexamination	

DEFAIX ET AL.

Art Unit

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ORIGINAL								INTERNATIONAL CLASSIFICATION										
CLASS SUBCLASS									С	LAIMED	NON-CLAIMED							
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CROSS REFERENCE(S)						_	_				-	+	+	-				
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☐ Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. ☐												□ R.1.	47		
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
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	2		18		34	11	50	24	66						
	3		19		35	12	51		67						
	4		20		38		52	25	68						
	5		21		37		53	26	69						
	6		22	- 1	38	13	54	27	70						
	7		23	2	39	14	55	28	71						
	8		24	3	40	15	56	29	72						
	9		25	4	41	16	57	30	73						
	10		28	- 5	42	17	58								
	11		27	6	43	18	59								
	12		28		44		60								
	13		29		45	19	61								
	14		30	7	46	20	62								
	16		21		47	24	62								

/Phillip H Nguyen/ Examiner.Art Unit 2191 (Assistant Examiner)	10/15/2009 (Date)	Total Claims Allowed:			
/Wei Y Zhen/ Supervisory Patent Examiner.Art Unit 2191	10/20/2009	O.G. Print Claim(s)	O.G. Print Figure		
(Primary Examiner)	(Date)	1	3		